IEEE SCC20 17-1 PLENARY Minutes Wednesday April 26, 2017

1) CALL TO ORDER (Mike Seavey)

Meeting called to order at 9:05 am by Mike Seavey

- 2) ANOUNCEMENTS (Teresa Lopes)
- 3) INTRODUCTIONS/ATTENDANCE SHEET (AII)
- 4) CALL FOR PATENTS (Mike Seavey)

Presented IEEE patent slides

5) 17-1 MEETING AGENDA (Mike Seavey)

No comments on agenda

6) WORKING GROUP PLANS FOR THIS MEETING

P1671.1 WG— A. Jain P1671.3 WG— I. Neag

<See IEEE 1671.1.3 Revision - SCC20 17-1.pptx>

Standard is done. Will review the changes and the process used to update the standards. Tried to address common feedback from users:

- It's complicated hard to do
- How do I do digital and serial buses

Summary of changes

- Eliminated redundancy between UUT description and Test Description
- Simplified description of data flows introduced variables
- Maximized use of type derivation switched from type derivation to choice (make more discoverable in XML editors / tools)
- Deleted rarely / never used elements and types

Make more accessible to new users

- Added normative clauses with "how to" clauses
 - Test program structure
 - Control flow
 - Data items and data flows
 - o Test behavior, use of 1641
 - o Fault Isolation how to reference from test trees
- Added more examples/samples
- Added informative clauses for digital and serial buses

Support for Digital and Serial buses

Could do it with 1641, but it wasn't obvious how to use it

- Support for static and simple dynamic
- New TSF class for DTIF complex dynamic tests
- Three specialized operations for Stimulate, Sense, Prove (aggregates stimulate, sense and compare works better when you want to do stuff in HW)
- Focus for serial buses was on exchanges
 - Not how you test the serial bus
 - Describe bus, messages and frames (repeated transmission of messages)
- Added TSF classes for common serial buses (RS-232, ARINC 429, Mil-Std-1553B)
- Created examples for common serial buses

Plan for the meeting

- Provide guidance to users on how to transition from trial-use standard to new standard
- Ideal for tools to help with migration
- Discuss additional examples for serial buses (Ethernet)

P1641.1a WG— C. *Gorringe*

Start ballot process by the end of May (will be tight). Amendment to standard has been created (list of instructions on how to modify the existing standard).

Still need to capture lessons learned – not a simple cut/paste because currently reference specific ATLAS – a couple of days of editorial work to get it sorted

Includes the digital TSFs create as part of the Test Description and UUT Description standards development

P1641 WG— C. *Gorringe*

First meeting since PAR was submitted. Review what would go in the revision. Make all changes backwards compatible. Address anomalies (areas where depending on implementation would yield different results)

Address feedback from users

Extend interface definition to include object model that could be used with .NET framework (make mapping to .NET a bit easier)

 P1636 WG M. Seavey

 P1636.1 WG M. Seavey

 P1636.2 WG M. Seavey

SIMICA family – all 3 documents have been updated. Review in Steering to go to ballot Test Results – no schema changes, EXPRESS removed, OWL ontology added MAI – same set of changes
Base document – gutted (removed all the EXPRESS)

Three documents now read as a family

Push to MEC after this meeting. Ballot all 3 simultaneously. Will make sure that this ballot doesn't overlap with TD and UD

There still is a SIMICA Common – it's a subset of ATML Common Schema uses same prefix so using either common is allowed

John and his graduate students have reviewed the changes to the document

1501.1 – single tier interface for 1505 standard

- Appendices were getting very specific about the resources connected to the interface
- Removing those appendices and focusing standard on describing the interface Have a redline package that working group will review and move ahead to ballot

1514 – intent was to come up with standard for ITA itself – not the interface, but the construction and structure (housing, cabling, etc.)

- Initally there was a lot of interest
- Interest has waned from both industry and DoD
- Plan is to withdraw the PAR for this working group

7) BALLOT RESOLUTION COMMITTEE PLANS FOR THIS MEETING

P1871.2 BRC– *C. Gorringe*

This one has been challenging. Went to ballot and got just enough approved. There were several negative ballots and many comments.

Document and schema have both been changed to address all comments and negative ballots.

Intent is to review changes to the schema and document and start the ballot recirculation (10 days)

8) New Items

Box.NET

- People are continuing to download the stale information from Box
- Once a standard goes to ballot, we archive what is in Box
- Go to IEEE to get the approved version of the standard

Working Group for 1671 Study Group to look at 1671 base document

- Changes to Wirelist
- What other changes would people be looking to make to the base standard?
 - Help us gage how much work so that we know when to pull the PAR
- Plan for the 1671 standards would be to pull a PAR for all 7 standards before they expire and do one last revision – DoD and MoD don't require that standards be active in order to use them

9) ADJOURN TO WORKING GROUPS

Meeting adjourned at 10:04 AM

IEEE 1671.1 WG IEEE 1671.3 WG Meeting

IEEE SCC20 11-1

North Reading, MA, April 2016

Work performed since last meeting

- Completed MEC
- Completed formation of ballot pools
- Submitted ballot packages to the IEEE on 4/24/2017

Overview of changes

Simplify

- Eliminated redundancy between Test Description and UUT Description
- Simplified description of data flows through the use of Variables
- Maximized the use of Common types
- Reduced the use of type derivation
- Deleted rarely / never used elements and types

Overview of changes...

- Make more accessible to new users
 - Created new normative clauses describing
 - Program structure
 - Control flow
 - Data & data flow
 - Test behavior
 - Fault isolation
 - Created new samples

Overview of changes...

- Enhance support for describing parallel digital tests
 - Created enhanced version of the TSF class from IEEE Std 1641 example library
 - Static tests
 - Simple dynamic tests
 - Created TSF class for DTIF
 - Complex dynamic tests
 - Created specialized operations
 - Stimulate
 - Sense
 - Prove
 - Created new example
 - Created new informative clause on describing digital tests

Overview of changes...

- Enhance support for describing serial digital bus exchanges
 - Added to UUT Description a capability to described serial buses and serial bus messages
 - Added to Test Description a capability to described serial frames
 - Created TSF classes for RS-232, ARINC 429, Mil-Std-1553B
 - Created specialized operations
 - Exchange
 - Data transfer operations
 - Created new, realistic examples for RS-232, ARINC 429, Mil-Std-155B
 - Created new informative clause on describing serial bus exchanges

Plan for this week

- Create list of changes from the previous revision
- Discuss support for version upgrade / downgrade
- Look at possibly creating additional examples for serial buses